# INTEGRATED CIRCUITS

# DATA SHEET

# **74LVC38A**Quad 2-input NAND gate (open drain)

Product specification Supersedes data of 2004 Mar 10 2004 Mar 22





# **Quad 2-input NAND gate (open drain)**

**74LVC38A** 

### **FEATURES**

- 5 V tolerant inputs for interfacing with 5 V logic
- Wide supply voltage range from 1.2 to 3.6 V
- CMOS low power consumption
- · Direct interface with TTL levels
- · Open-drain outputs
- Inputs accept voltages up to 5.5 V
- Complies with JEDEC standard no. 8-1A
- Specified from -40 to +85 °C and -40 to +125 °C.

### DESCRIPTION

The 74LVC38A is a high-performance, low-power, low-voltage, Si-gate CMOS device, superior to most advanced CMOS compatible TTL families.

Inputs can be driven from either 3.3 or 5 V devices. This feature allows the use of these devices as translators in a mixed 3.3 and 5 V environment.

The 74LVC38A provides the 2-input NAND function.

The outputs of the 74LVC38A devices are open drain and can be connected to other open-drain outputs to implement active-LOW wired-OR or active-HIGH wired-AND functions.

# **QUICK REFERENCE DATA**

GND = 0 V;  $T_{amb} = 25 \, ^{\circ}C$ ;  $t_r = t_f \le 2.5 \, \text{ns}$ .

SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t <sub>PZL</sub>	propagation delay nA, nB to nY	$C_L = 50 \text{ pF}; V_{CC} = 3.3 \text{ V}$	1.7	ns
t <sub>PLZ</sub>	propagation delay nA, nB to nY	$C_L = 50 \text{ pF}; V_{CC} = 3.3 \text{ V}$	2.3	ns
C <sub>I</sub>	input capacitance		4.0	pF
C <sub>PD</sub>	power dissipation capacitance per gate	V <sub>CC</sub> = 3.3 V; notes 1 and 2	5.5	pF

# Notes

1.  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$$
 where:

f<sub>i</sub> = input frequency in MHz;

f<sub>o</sub> = output frequency in MHz;

C<sub>L</sub> = output load capacitance in pF;

V<sub>CC</sub> = supply voltage in Volts;

N = total load switching outputs;

 $\Sigma(C_L \times V_{CC}^2 \times f_0)$  = sum of the outputs.

2. The condition is  $V_I = GND$  to  $V_{CC}$ .

# ORDERING INFORMATION

TYPE NUMBER		PACKAGE											
THENOMBER	TEMPERATURE RANGE	PINS	PACKAGE	MATERIAL	CODE								
74LVC38AD	−40 to +125 °C	14	SO14	plastic	SOT108-1								
74LVC38ADB	−40 to +125 °C	14	SSOP14	plastic	SOT337-1								
74LVC38APW	−40 to +125 °C	14	TSSOP14	plastic	SOT402-1								
74LVC38ABQ	−40 to +125 °C	14	DHVQFN14	plastic	SOT762-1								

# Quad 2-input NAND gate (open drain)

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# **FUNCTION TABLE**

See note 1.

INP	UTS	OUTPUTS
nA	nY	
L	L	Z
L	Н	Z
Н	L	Z
Н	Н	L

# Note

1. H = HIGH voltage level;

L = LOW voltage level:

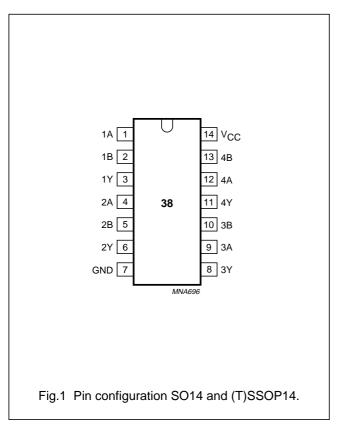
Z = high-impedance OFF-state.

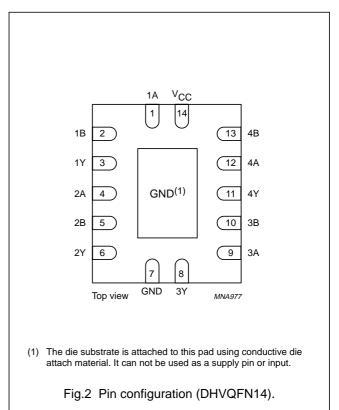
# **PINNING**

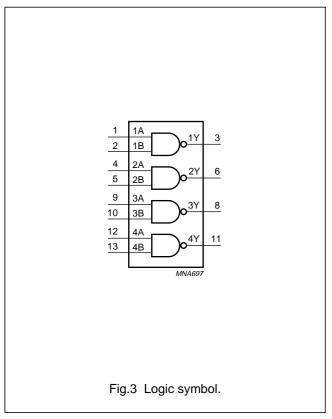
PIN	SYMBOL	DESCRIPTION
1	1A	data input
2	1B	data input
3	1Y	data output
4	2A	data input
5	2B	data input
6	2Y	data output
7	GND	ground (0 V)
8	3Y	data output
9	3A	data input
10	3B	data input
11	4Y	data output
12	4A	data input
13	4B	data input
14	V <sub>CC</sub>	supply voltage

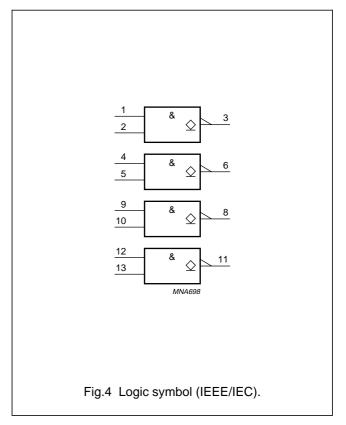
# Quad 2-input NAND gate (open drain)

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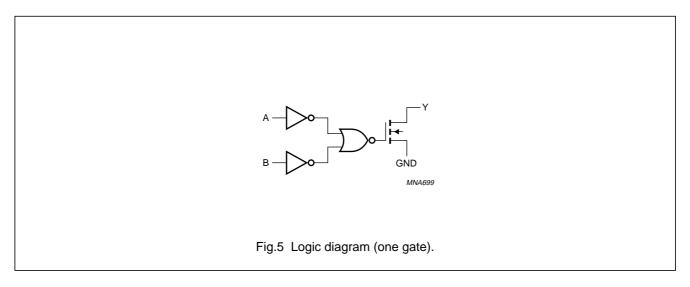






# Quad 2-input NAND gate (open drain)

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# RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage	for maximum speed performance	2.7	3.6	V
		for low-voltage applications	1.2	3.6	V
VI	input voltage		0	5.5	V
Vo	output voltage		0	5.5	V
T <sub>amb</sub>	operating ambient temperature		-40	+125	°C
t <sub>r</sub> , t <sub>f</sub>	input rise and fall times	V <sub>CC</sub> = 1.2 to 2.7 V	0	20	ns/V
		V <sub>CC</sub> = 2.7 to 3.6 V	0	10	ns/V

# **LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>CC</sub>	supply voltage		-0.5	+6.5	V
I <sub>IK</sub>	input diode current	V <sub>I</sub> < 0	_	-50	mA
VI	input voltage	note 1	-0.5	+6.5	V
I <sub>OK</sub>	output diode current	V <sub>O</sub> < 0	_	-50	mA
Vo	output voltage	note 1	-0.5	+6.5	V
Io	output sink current	$V_O = 0$ to $V_{CC}$	_	50	mA
I <sub>CC</sub> , I <sub>GND</sub>	V <sub>CC</sub> or GND current		_	±100	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	power dissipation	$T_{amb} = -40 \text{ to } +125 \text{ °C}; \text{ note } 2$	_	500	mW

# **Notes**

- 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
- 2. For SO14 packages: above 70 °C derate linearly with 8 mW/K.

For (T)SSOP14 packages: above 60 °C derate linearly with 5.5 mW/K.

For DHVQFN14 packages: above 60 °C derate linearly with 4.5 mW/K.

# Quad 2-input NAND gate (open drain)

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# **DC CHARACTERISTICS**

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

CVMDOL	DADAMETED	TEST CONDITION	ONS	NAIN!	TVD	MAY	LINIT
SYMBOL	PARAMETER	OTHER	V <sub>CC</sub> (V)	MIN.	TYP.	MAX.	UNIT
T <sub>amb</sub> = -40	) to +85 °C; note 1				•	•	'
V <sub>IH</sub>	HIGH-level input voltage		1.2	V <sub>CC</sub>	_	_	V
			2.7 to 3.6	2.0	_	_	V
V <sub>IL</sub>	LOW-level input voltage		1.2	_	_	GND	V
			2.7 to 3.6	_	_	0.8	V
$V_{OL}$	LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$					
		I <sub>O</sub> = 100 μA	2.7 to 3.6	_	GND	0.20	V
		I <sub>O</sub> = 12 mA	2.7	_	-	0.40	V
		I <sub>O</sub> = 24 mA	3.0	_	-	0.55	V
ILI	input leakage current	V <sub>I</sub> = 5.5 V or GND	3.6	_	±0.1	±5	μΑ
I <sub>OZ</sub>	3-state output OFF-state current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = 5.5 \text{ V or GND}$	3.6	_	0.1	±10	μΑ
I <sub>CC</sub>	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	3.6	_	0.1	10	μΑ
$\Delta I_{CC}$	additional quiescent supply current per input pin	$V_I = V_{CC} - 0.6 \text{ V}; I_O = 0$	2.7 to 3.6	_	5	500	μΑ
T <sub>amb</sub> = -40	) to +125 °C		•	•	•	•	•
V <sub>IH</sub>	HIGH-level input voltage		1.2	V <sub>CC</sub>	-	_	V
			2.7 to 3.6	2.0	_	_	V
V <sub>IL</sub>	LOW-level input voltage		1.2	_	_	GND	V
			2.7 to 3.6	_	_	0.8	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>					
		I <sub>O</sub> = 100 μA	2.7 to 3.6	_	_	0.3	V
		I <sub>O</sub> = 12 mA	2.7	_	_	0.6	V
		I <sub>O</sub> = 24 mA	3.0	_	_	0.8	V
ILI	input leakage current	V <sub>I</sub> = 5.5 V or GND	3.6	_	-	±20	μΑ
l <sub>OZ</sub>	3-state output OFF-state current	$V_I = V_{IH} \text{ or } V_{IL};$ $V_O = 5.5 \text{ V or GND}$	3.6	_	_	±20	μА
I <sub>CC</sub>	quiescent supply current	$V_I = V_{CC}$ or GND; $I_O = 0$	3.6	_	-	40	μΑ
$\Delta I_{CC}$	additional quiescent supply current per input pin	$V_I = V_{CC} - 0.6 \text{ V}; I_O = 0$	2.7 to 3.6	-	-	5000	μА

# Note

1. All typical values are measured at  $V_{CC}$  = 3.3 V and  $T_{amb}$  = 25  $^{\circ}C.$ 

# Quad 2-input NAND gate (open drain)

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# **AC CHARACTERISTICS**

 $GND=0~V;~t_r=t_f\leq 2.5~ns.$ 

OVMBOL	DADAMETED	TEST COND	ITIONS		TVD	DA A V		
SYMBOL	PARAMETER	WAVEFORMS	V <sub>CC</sub> (V)	MIN.	TYP	MAX.	UNIT	
T <sub>amb</sub> = -40	) to +85 °C; note 1		•	•		•	•	
t <sub>PZL</sub>	propagation delay nA, nB to nY	see Figs 6 and 7	1.2	_	5.7	_	ns	
			2.7	0.5	1.7	2.9	ns	
			3.0 to 3.6	0.5	1.7 <sup>(2)</sup>	3.0	ns	
t <sub>PLZ</sub>	propagation delay nA, nB to nY	see Figs 6 and 7	1.2	_	4.8	_	ns	
			2.7	1.0	2.6	3.8	ns	
			3.0 to 3.6	1.0	2.3(2)	3.6	ns	
t <sub>sk(0)</sub>	skew	note 3		_	_	1.0	ns	
T <sub>amb</sub> = -40	) to +125 °C			•				
t <sub>PZL</sub>	propagation delay nA, nB to nY	see Figs 6 and 7	1.2	_	_	_	ns	
			2.7	0.5	_	4.0	ns	
			3.0 to 3.6	0.5	_	4.0	ns	
t <sub>PLZ</sub>	propagation delay nA, nB to nY	see Figs 6 and 7	1.2	_	_	_	ns	
			2.7	1.0	_	5.0	ns	
			3.0 to 3.6	1.0	_	4.5	ns	
t <sub>sk(0)</sub>	skew	note 3		-	_	1.5	ns	

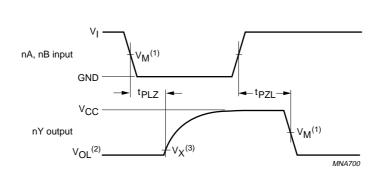
# Notes

- 1. All typical values are measured at  $T_{amb}$  = 25 °C.
- 2. These typical values are measured at  $V_{CC}$  = 3.3 V.
- Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.

# Quad 2-input NAND gate (open drain)

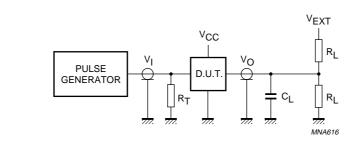
74LVC38A

# **AC WAVEFORMS**



- (1)  $V_M = 1.5 \text{ V at } V_{CC} \ge 2.7 \text{ V}.$   $V_M = 0.5 V_{CC} \text{ at } V_{CC} < 2.7 \text{ V}.$
- (2)  $V_{OL}$  and  $V_{OH}$  are typical output voltage drop that occur with the output load.
- (3)  $V_X = V_{OL} + 0.3 \text{ V at } V_{CC} \ge 2.7 \text{ V}.$   $V_X = V_{OL} + 0.15 \text{ V at } V_{CC} < 2.7 \text{ V}.$

Fig.6 The input nA, nB to output nY propagation delays.



V <sub>CC</sub>	V <sub>EXT</sub>	Vı	C <sub>L</sub>	R <sub>L</sub>
1.2	$2 \times V_{CC}$	V <sub>CC</sub>	30 pF	$500~\Omega^{(1)}$
2.7	6 V	2.7 V	50 pF	500 Ω
3.3 to 3.6	6 V	2.7 V	50 pF	500 Ω

# Note

1. The circuit performs better when  $R_L = 1000 \ \Omega$ .

Definitions for test circuits:

R<sub>L</sub> = Load resistor.

C<sub>L</sub> = Load capacitance including jig and probe capacitance.

 $R_T$  = Termination resistance should be equal to the output impedance  $Z_0$  of the pulse generator.

 $t_r$  =  $t_f$   $\leq$  2.5 ns; when measuring  $f_{max}$ , there is no constraint on  $t_r$ ,  $t_f$  with 50% duty factor.

Fig.7 Load circuitry for switching times.

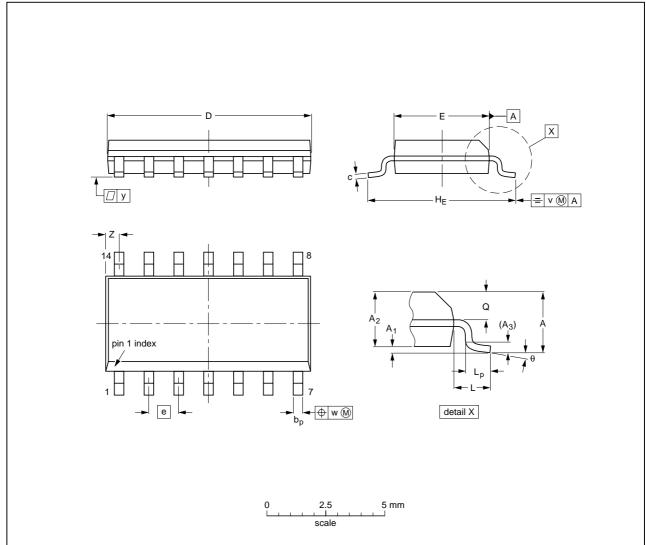
# Quad 2-input NAND gate (open drain)

74LVC38A

# **PACKAGE OUTLINES**

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



### DIMENSIONS (inch dimensions are derived from the original mm dimensions)

	Similar of the difference of the deliver from the original film differences																	
UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	Q	v	w	у	z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

### Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

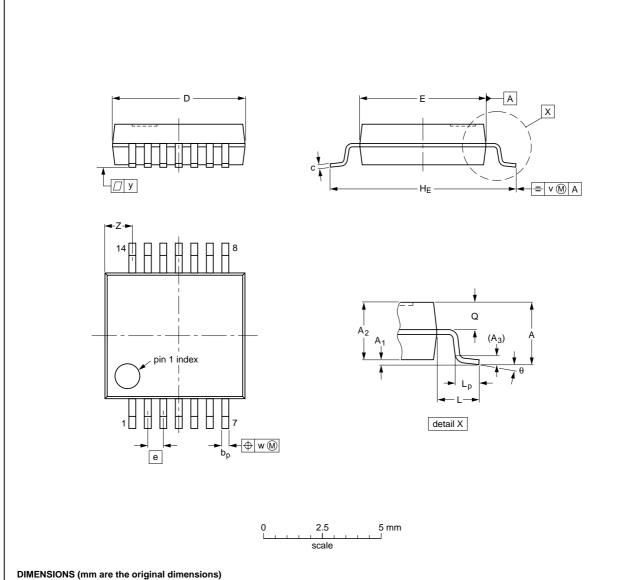
OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT108-1	076E06	MS-012				<del>99-12-27</del> 03-02-19	

# Quad 2-input NAND gate (open drain)

74LVC38A

SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

SOT337-1



UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(1)</sup>	е	HE	L	Lp	ø	v	w	у	Z <sup>(1)</sup>	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	6.4 6.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	1.4 0.9	8° 0°

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	IOOUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT337-1		MO-150				<del>99-12-27</del> 03-02-19	

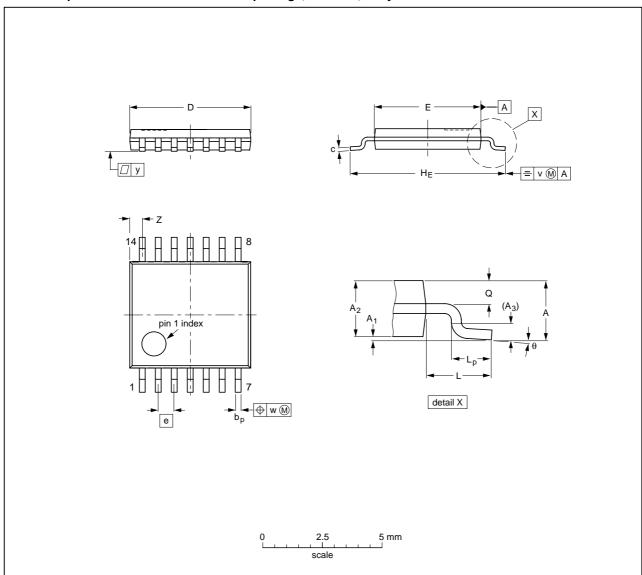
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# Quad 2-input NAND gate (open drain)

74LVC38A

TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



# **DIMENSIONS (mm are the original dimensions)**

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	bp	С	D <sup>(1)</sup>	E <sup>(2)</sup>	е	HE	L	Lp	ø	v	w	у	Z <sup>(1)</sup>	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

# Notes

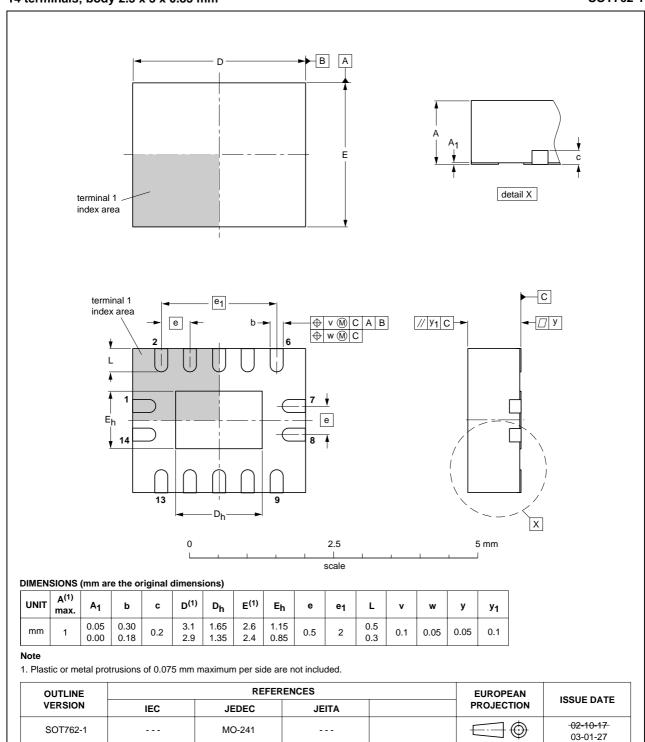
- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT402-1		MO-153				<del>99-12-27</del> 03-02-18	

# Quad 2-input NAND gate (open drain)

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DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm SOT762-1



# Quad 2-input NAND gate (open drain)

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### **DATA SHEET STATUS**

LEVEL	DATA SHEET STATUS <sup>(1)</sup>	PRODUCT STATUS(2)(3)	DEFINITION
I	Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
II	Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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- 2. The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.
- 3. For data sheets describing multiple type numbers, the highest-level product status determines the data sheet status.

### **DEFINITIONS**

**Short-form specification** — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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